

Abstract**Device and method for determining the sheet resistance of samples**

A device and method for determining the sheet resistance of samples, in particular wafers and other two-dimensional objects, comprising a means for measuring the conductivity of the sample according to the eddy current technique, wherein the sample is introducible into a gap for measurement, and comprising a means for measuring the position of the sample in the gap for measurement and a computing means for determining the sheet resistance on the basis of the measured conductivity and of the position of the sample in the gap for measurement.